

Product Change Notification - BCD0500017 - JAON-20BQVK768

Date:

23 Dec 2019

Product Category:

Power Management - Power Switches

Affected CPNs:



Notification subject:

CCB 2837 Final Notice: Release to production of listed Micrel Power Switches product type manufactured with the BCD05 process technology to Fabrication site (FAB 5).

Notification text:

PCN Status:

Final notification

Note: This final PCN only pertains to the products listed in this PCN. Additional final PCNs may be issued for this combination of product type and process technology.

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Release to production of listed Micrel Power Switches product type manufactured with the BCD05 process technology to Fabrication site (FAB 5).

Pre Change:

Fabricated at Micrel fabrication site (San Jose, CA, USA) (SJ) using 6 inch wafers.

Post Change:

Fabricated at Atmel Fabrication site FAB 5 (Colorado Springs, CO, USA) (COS) using 6 inch wafers

Pre and Post Change Summary:

Pre and Post Change Summary:									
	Pre Change		Change						
		Primary Fab Location:	Backup Fab Locations:						
Fabrication Location	Micrel Fabrication Site	Atmel Fabrication site	Microchip Fabrication						
rabilication Location	(San Jose, CA, USA)	FAB 5 (Colorado	Sites (Tempe, AZ and						
		Springs, CO USA)	Gresham, OR, USA)						
Wafer Diameter	6 inches (150 mm)	6 inches (150 mm)	8 inches (200 mm)						
Quality certification	ISO9001	ISO9001/TS16949	ISO/TS16949						
Data sheet /	No Change	No Chango	No Change						
specifications	No Change	No Change	No Change						
Design/layout	No Change	No Change	No Change						
Die Size	No change	No change	No change						
Final test program	No change	No change	No change						
Package Type/MSL	No Change	No Change	No Change						

Impacts to Data Sheet:

No impact anticipated.

Change Impact:

None

Reason for Change:



To improve productivity with the closure of the Micrel fab (SJ) as part of the integration of Micrel and Microchip.

Change Implementation Status:

In Progress

Estimated First Ship Date:

As identified for each CPN listed in the attached parts list.

Estimated First Ship Date (EFSD) are identified for each catalog part numbers (CPN) listed in the attached parts list. This can be found in the attachments field below labeled as PCN # Affected CPN.

Summary Time Table of notable events to date:

	De	cen	nbe	r 20)16	->				December 2019				January 2020						
Workweek	48	49	50	51	52		18	19	20	21		49	50	51	52	01	02	03	04	05
Initial PCN				Х																
Issue Date				^																
Qualification																				
Report																				
Availability and																				
Intermediate							Х													
PCN issue date																				
<u>JAON-</u>																				
20BQVK768																				
Final PCN																				
Issue Date																				
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JAON-																				
20BQVK768 -																				
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Estimated First																	the			
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Method to Identify Change:

Traceability code.

Qualification Report:

Please open the attachments included with this PCN labeled as PCN # Qual Report.

Revision History:

December 23, 2016: Issued initial notification.

May 4, 2017: Issued intermediate notification. Attached the Qualification Report.

December 23, 2019: Issued final notification as PCN number JAON-20BQVK768 - BCD0500017 for listed Micrel's Power Switches products manufactured with the BCD05 process technology to Fabrication site (FAB 5). Provided estimated first ship date (EFSD) for each CPN listed in the attached parts list.

The change described in this PCN does not alter Micrel's or Atmel's or Microchip's current regulatory compliance regarding the material content of the applicable products.



Attachment(s):

PCN JAON-20BQVK768-BCD0500017 Affected CPN.pdf PCN JAON-20BQVK768-BCD0500017 Qual Report.pdf PCN JAON-20BQVK768-BCD0500017 Affected CPN.xls

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

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If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

JAON-20BQVK768 - CCB 2837 Final Notice: Release to production of listed Micrel Power Switches product type manufactured with the BCD05 process technology to Fabrication site (FAB 5).
Affected Catalog Part Numbers (CPN)
MIC94161YCS-TR MIC94164YCS-TR
MICHTOTICS IX
Date: Sunday, December 22, 2019

JAON-20BQVK768-BCD0500017 – CCB 2837 Final Notice: Release to production of listed Micrel Power Switches product type manufactured with the BCD05 process technology to Fabrication site (FAB 5).

Affected Catalog Part Numbers (CPN)

PCN_JAON-20BQVK768-BCD0500017							
CATALOG_PART_NBR	Estimated First Ship Date (EFSD)						
MIC94161YCS-TR	January 06, 2020						
MIC94164YCS-TR	January 06, 2020						



QUALIFICATION REPORT SUMMARY

PCN #: JAON-20BQVK768 - BCD0500017

Date April 6, 2017

Qualification of Fabrication site (FAB 5) for Micrel products manufactured with the BCD05 process technology.

PART NUMBER	PACKAGE TYPE	ASSEMBLY LOCATION	FAB LOCATION	PROCESS NAME
MIC2104YML	QFN33-16L	UNISEM, MALAYSIA	MICROCHIP FAB-5 Colorado Springs	BCD05/CSI05

DIE QUALIFICATION RESULTS

TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	168 HR Rej/ss	500 HR Rej/ss	1000 HR Rej/ss	COMMENTS
HTOL	JESD22, Method 108	1643	R6X0362	0/82	0/82	0/82	*Units went straight to 1000 hours. No read
High Temperature Operating Life Test	Ta = +125°C	1702	UNIS173100082.000 6Y2663 UNIS174200177.100B	0/80	_*	0/80	out at 500 hours.
	Vcc = +75V	1703	6Y0748 UNIS174300027.000	0/79	_*	0/78**	

^{*}Lot 2 under 500HR went straight to 1000 HR skipping the 500 HR read.

^{**} Lot 3 started with 79 units, one device removed at 168 hours, 78 units went straight to straight to 1000 hours

TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	168 HR Rej/ss	408 HR Rej/ss	COMMENTS
HTOL	JESD22, Method 108	1702	R6X0362 UNIS173100082.000	0/77	0/77	*77 units went straight to 408 hours. No read out at 168 hours.
High Temperature Operating Life Test	Ta = +150°C	1703	B6Y0748			
	Vcc = +75V		UNIS174300027.000	_*	0/77	

ELECTROSTATIC DISCHARGE

TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	STRESS	RESULT Rej/ss	COMMENTS	
ESD-HBM Human Body Model ATE Test @ Room +25C	R= 1500 Ohms C= 100 pF 1X +/- Voltage	1643	R6X0362 UNIS173100082.000	+/-1000V	0/3	Note: ESD ratings are, device specific. All products, qualified on the 6" Micrel, process technologies at, Microchip Fabs will have the, same or better ESD and, Latch-up performance	
ESD-CDM Charged Device Model ATE Test @ Room +25C	JESD22-C101 1X +/- Voltage	1643	R6X0362 UNIS173100082.000	+/-1500V	0/3	as the 6" products fabricated at San Jose wafer fabrication site.	
TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	STRESS	RESULT Rej/ss	COMMENTS	
LATCH-UP	JESD-78 A = +25°C	1643	R6X0362 UNIS173100082.000	I/O LU O/V LU	0/6 0/6	Same as SJ 6 inch	

TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	Rej/ss	COMMENTS
Level 1 Pre-conditioning Flow Use samples to perform	JESD22-A113	1643	R6X0362 UNIS173100082.000	0/375	
UHAST/BHAST/TCY		1702	6Y2663 UNIS174200177.100	0/272	
		1703	B6Y0748 UNIS174300027.000	0/431	
TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	96 HR Rej/ss	COMMENTS
UHAST	Ta= +131°C/85%RH	1643	R6X0362 UNIS173100082.000	0/82	
With Level 1 Pre- conditioning	JESD22-A118 (UNBIASED)	1702	6Y2663 UNIS174200177.100	0/82	
Tpeak + 260°C 3X Reflow		1703	B6Y0748 UNIS174300027.000	0/82	
TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	96 HR Rej/ss	COMMENTS
BHAST	JESD22-A110 (BIASED)	1643	R6X0362 UNIS173100082.000	0/82	
With Level 1 Pre- conditioning	Ta= +130°C/85%RH	1702	6Y2663 UNIS174200177.100	0/82	
Tpeak + 260°C 3X Reflow	Vcc = +75V	1703	B6Y0748 UNIS174300027.000	0/82	
TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	500 CY Rej/ss	COMMENTS
TEMP CYCLE	JESD22-A104	1643	R6X0362 UNIS173100082.000	0/82	
With Level 1 Pre- conditioning Tpeak + 260°C 3X Reflow	Ta = -65°C / +150°C	1702	6Y2663 UNIS174200177.100	0/82	
		1703	B6Y0748 UNIS174300027.000	0/82	
TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	500 HR Rej/ss	COMMENTS
HTSL	JESD22-A103	1643	R6X0362 UNIS173100082.000	0/50	
High Temperature Storage Life	Ta = +175°C				
TEST DESCRIPTION	METHOD/CONDITIONS	DATE CODE	LOT ID.	1000 HR Rej/ss	COMMENTS
HTSL	JESD22-A103	1643	R6X0362 UNIS173100082.000	0/50	
High Temperature Storage Life	Ta = +150°C		UNIS 173 100002.000		
FLAMMABILITY	UL-94V-0				ee the UL website on-line list of ficate of Compliance from the assem
	Certified		d we verify the certifications		3. 33